

<b>INFORMATION DISCLOSURE STATEMENT TRANSMITTAL</b>  To Commissioner For Patents Enclosed herewith is a Form PTO-1449, any required copies of documents listed thereon, and any concise explanation of their relevance is indicated below per 37 CFR 1.97.	<b>Application Number</b>	
	<b>Filing Date</b>	<b>10/587645</b>
	<b>First Named Inventor</b>	SCARPA, ANDREA
	<b>Group Art Unit</b>	
	<b>Examiner Name</b>	
	<b>Atty. Docket Number</b>	<b>NL040019US1</b>

U.S. PATENT DOCUMENTS					
Examiner Initials*	Cite No. <sup>1</sup>	Document Number No.-Kind Code <sup>2</sup> (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns Lines, Where Relevant Passages or Relevant Figures Appear
		US-			
		US-			
		US-			
		US-			
		US-			
		US-			

FOREIGN PATENT DOCUMENTS						
Examiner Initials*	Cite No. <sup>1</sup>	Document Number (try <sup>3</sup> -no. <sup>4</sup> -kind <sup>5</sup> , if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of cited document	Pages, Columns Lines, Where Relevant Passages or Relevant Figures Appear	T <sup>6</sup>

NON-PATENT LITERATURE DOCUMENTS						
Examiner Initials*	Cite No. <sup>1</sup>	Include name of the author (in capital letters), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.				T <sup>6</sup>
	1	DE MANARI I ET AL: "A TEST PATTERN FOR THREE-DIMENSIONAL LATCH-UP ANALYSIS"; MICROELECTRONIC TEST STRUCTURES 1993 ICMTS 1993; PROCEEDINGS OF THE 1993 INTERNATIONAL CONFERENCE ON SITGES, SPAIN 22-25 MARCH 1993; N.Y. USA; IEEE US 22 MARCH 1993; PP 103-109.				
	2	MUNARI DE ET AL: "DESIGN AND SIMULATION OF A TEST PATTERN FOR THREE-DIMENSIONAL LATCH-UP ANALYSIS"; MICROELECTRONICS JOURNAL MACKINTOSH PUBLICATIONS LTD; LUTON GB; VOL. 24, NO. 7; 1 NOV. 1993; PP 759-771.				

<b>Examiner Signature</b>		<b>Date Considered</b>	
---------------------------	--	------------------------	--

\* EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.